

APPROVAL SHEET

MULTILAYER CERAMIC CAPACITORS

High Q / Low ESR Series (HH)

0201 to 0805 Sizes

NP0 Dielectric

Halogen Free & RoHS Compliance

*Contents in this sheet are subject to change without prior notice.



Approval Sheet

1. INTRODUCTION

MLCC consists of a conducting material and electrodes. To manufacture a chip-type SMT and achieve miniaturization, high density and high efficiency, ceramic condensers are used.

WTC HH series MLCC is used at high frequencies generally have a small temperature coefficient of capacitance, typical within the ±30ppm/°C required for NP0 (C0G) classification and have excellent conductivity internal electrode. Thus, WTC HH series MLCC will be with the feature of low ESR and high Q characteristics.

2. FEATURES

- a. High Q and low ESR performance at high frequency.
- b. Quality improvement of telephone calls for low power loss and better performance.

3. APPLICATIONS

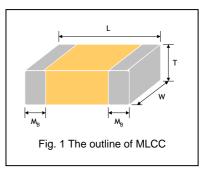
- a. Mobile telecommunication: Mobile phone, WLAN.
- b. RF module: Power amplifier, VCO.
- c. Tuners.

4. HOW TO ORDER

<u>HH</u>	<u>15</u>	<u>N</u>	<u>100</u>	<u>G</u>	<u>500</u>	<u>C</u>	Ī
<u>Series</u>	<u>Size</u>	Dielectric	Capacitance	<u>Tolerance</u>	Rated voltage	<u>Termination</u>	<u>Packaging</u>
HH=High Q/ Low ESR	03=0201 (0603) 15=0402 (1005) 18=0603 (1608) 21=0805 (2012)	N=NP0 (COG)	Two significant digits followed by no. of zeros. And R is in place of decimal point. PASSIVE SY: eg.: R47=0.47pF 0R5=0.5pF 1R0=1.0pF 100=10x10° =10pF	A=±0.05pF B=±0.1pF C=±0.25pF D=±0.5pF F=±1% G=±2% J=±5%	Two significant digits followed by no. of zeros. And R is in place of decimal point. 100=10 VDC 160=16 VDC 250=25 VDC 500=50 VDC 101=100 VDC 201=200 VDC 251=250 VDC 501=500 VDC	C=Cu/Ni/Sn	T=7" reeled G=13" reeled

5. EXTERNAL DIMENSIONS

Size Inch (mm)	L (mm)	W (mm)	T (mm)/Symbol		Remark	M _B (mm)
0201 (0603)	0.6±0.03	0.3±0.03	0.3±0.03	L	#	0.15±0.05
0402 (1005)	1.00±0.05	0.50±0.05	0.50±0.05	N	#	0.25 +0.05/-0.10
	1.60±0.10	0.80±0.10	0.80±0.07	.80±0.07 S		
0603 (1608)	1.60 +0.15/-0.10	0.80 +0.15/-0.10	0.80 +0.15/-0.10	х		0.40±0.15
			0.60±0.10	А		
0805 (2012)	2.00±0.15	1.25±0.10	0.80±0.10	В		0.50±0.20
			1.25±0.10	D	#	



6. GENERAL ELECTRICAL DATA

Dielectric	NPO /				
Size	0201, 0402, 0603, 0805				
Capacitance*	0.5pF to 3300pF				
	Cap≤5pF [#] : A (±0.05pF), B (±0.1pF), C (±0.25pF)				
Capacitance tolerance	5pF <cap<10pf: (±0.25pf),="" (±0.5pf)<="" c="" d="" td=""></cap<10pf:>				
	Cap≥10pF: F (±1%), G (±2%), J (±5%)				
Rated voltage (WVDC)	10V, 16V, 25V, 50V, 100V, 200V, 250V, 500V, 630V				
2*	Cap<30pF: Q≥400+20C				
Q*	Cap≥30pF: Q≥1000				
Insulation resistance at Ur	≥10GΩ or RxC≥100Ω-F whichever is smaller.				
Operating temperature	-55 to +125℃// 10 lOg				
Capacitance change	±30ppm				
Termination	Ni/Sn (lead-free termination)				

^{#1:} NP0, 0.1pF product only provide B tolerance

 $Apply \ 1.0 \pm 0.2 Vrms, \ 1.0 MHz \pm 10\% \ for \ Cap \leq 1000 pF \ and \ 1.0 \pm 0.2 Vrms, \ 1.0 kHz \pm 10\% \ for \ Cap > 1000 pF.$

7. PACKAGING DIMENSION AND QUANTITY

Size	Thickness (mm)/Sym	Pape	r tape	Plastic tape		
Size	THICKHESS (HIIII)/SYIII	7" reel	13" reel	7" reel	13" reel	
0201	0.30±0.03	L	15,000	70,000	-	-
0402	0.50±0.05	N	10,000	50,000	-	-
0000	0.80±0.07	S	4.000	45.000		
0603	0.80 +0.15/-0.10	Х	4,000	15,000	-	-
	0.60±0.10	Α	4.000	45.000		
0805	0.80±0.10	В	4,000	15,000	-	-
	1.25±0.10	D	-	-	3,000	10,000

Unit: pieces

[#] Reflow soldering only is recommended.

^{*} Measured at the conditions of 25℃ ambient temper ature and 30~70% related humidity.

^{** 0402,} Capacitance <0.5pF: On request.

8. CAPACITANCE RANGE

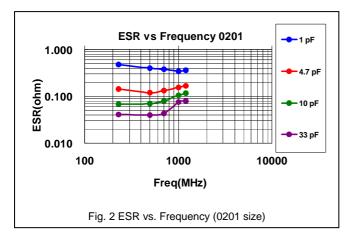
	DIELECTRIC										NP0									
	SIZE		02					02				0603					08			
	Rated Voltage	10	16	25	50	16	25	50	100	16	25	50	100	200	50		200	250	500	630
	0.5pF (0R5)	L	L	L	L	N	N	N	N	S	S	S	S	S	В	В				
	0.6pF (0R6)	L	L	L	L	N	N	N	N	S	S	S	S	S	В	В				
	0.7pF (0R7)	L	L	L	L	N	N	N	N	S	S	S	S	S	В	В				
	0.8pF (0R8)	L	L	L	L	N	N	N	N	S	S	S	S	S	В	В				
	0.9pF (0R9)	L	L	L	L	N	N	N	N	S	S	_	S	S	В	В	_			
	1.0pF (1R0) 1.2pF (1R2)	L	L	L	L	N N	N N	N N	N N	S	S	S	S	S	B	В	B	B B	B B	B B
	1.5pF (1R5)	L	L	L	L	N	N	N	N	S	S	S	S	S	В	В	В	В	В	В
	1.8pF (1R8)	L	L	L	L	N	N	N	N	S	S	S	S	S	В	В	В	В	В	В
	2.2pF (2R2)	L	L	L	L	N	N	N	N	S	S	S	S	S	В	В	В	В	В	В
	2.7pF (2R7)	L	L	L	L	N	N	N	N	S	S	S	S	S	В	В	В	В	В	В
	3.3pF (3R3)	L	L	L	L	N	N	N	N	S	S	S	S	S	В	В	В	В	В	В
	3.9pF (3R9)	L	L	L	L	N	N	N	N	S	S	S	S	S	В	В	В	В	В	В
	4.7pF (4R7)	L	L	L	L	N	N	N	N	S	S	S	S	S	В	В	В	В	В	В
	5.6pF (5R6)	L	L	L	L	N	N	N	N	S	S	S	S	S	В	В	В	В	В	В
	6.8pF (6R8)	L	L	L	L	N	N	N	N	S	S	S	S	S	В	В	В	В	В	В
	8.2pF (8R2)	L	L	L	L	N	N	N	N	S	S	S	S	S	В	В	В	В	В	В
	10pF (100)	Ē	L	L	L	N	N	N/	N	S	S	S	S	S	В	В	В	В	В	В
	12pF (120)	L	L	L	L	N,	~NO	NE	N	\$	S	S	S		В	В	В	В	В	В
	15pF (150)	L	L	L	L	N	N	N	πNZ	S	S	S	S		В	В	В	В	В	В
	18pF (180)	L	L	L	L	YN	N	N	$>_{N}$	7 s	S	S	S		В	В	В	В	В	В
	22pF (220)	L	L	L	/KW	N	N	N	N	S	/S	S	S		В	В	В	В	В	В
Se	27pF (270)	L	L	L	12/4	/ N	N	N	N	S	S	S	S		В	В	В	В	В	В
Capacitance	33pF (330)	L	L	L/	L	N/	N	N	N	S	S	S	S		В	В	В	В	В	В
aci	39pF (390)					N	N	N	N	S	S	S	S		В	В	В	В	В	В
Cak	47pF (470)					N	N	N	N	S	S	S	S		В	В	В	В	В	В
	56pF (560)				8	Ν	N	N S	N	S	S	S	\$		В	В	В	В	В	В
	68pF (680)				2	N	N	N	N	S	S	Cs i	S		В	В	В	В	В	В
	82pF (820)			'	6	N	N	N	N	S	S	S	S		В	В	В	В	В	В
	100pF (101)					οN	N	N	N	S	S	S	S		В	В	В	В	В	В
	120pF (121)					N	No.	N	N	S	S	S	S		D	D	D	D	D	D
	150pF (151)					N	/ N	/N () N 9	S	S	S	S		D	D	D	D	D	D
	180pF (181)					N	/_N/_	N	N	SIT)\s	S	S				D	D	D	D
	220pF (221)					N	N"	N.	N	PLSIM	S	S	S		<u> </u>		D	D	D	D
	270pF (271)					N	N	N		S	S	S	S				D	D	D	D
	330pF (331)					N	N	N		S	S	S	S		<u> </u>		D	D	D	D
	390pF (391)					N	N	N		S	S	S	S				D	D	D	D
	470pF (471)					N	N	N		S	S	S	S							
	560pF (561)									S	S	S	S							
	680pF (681)									S	S	S	S		-					
	820pF (821)									S	S	S	S		-					
	1,000pF (102)									X	X	X	<u> </u>							
	1,200pF (122)									X	X	X			<u> </u>					
	1,500pF (152)									X	X	X			-					
	1,800pF (182)									X	X	X								
	2,200pF (222) 2,700pF (272)									X	X	X			 					
	3,300pF (332)									X	X	X			-					
	ა,ასსტი (აა2)									^	_ ^	_ ^			l					

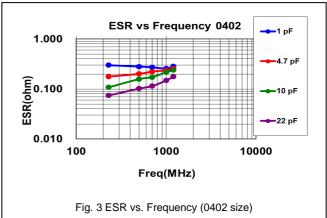
^{1.} The letter in cell is expressed the symbol of product thickness.

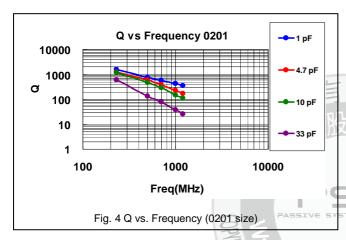
^{2. 0201 &}amp; 0402, Capacitance < 0.5pF: On request.

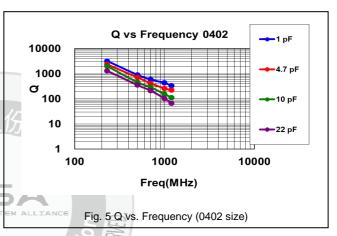
^{3.} For more information about products with special capacitance or other data, please contact WTC local representative.

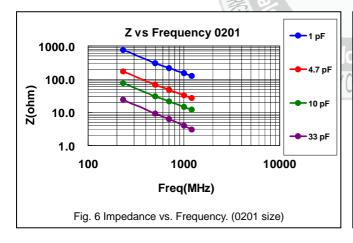
9. ELECTRICAL CHARACTERISTICS

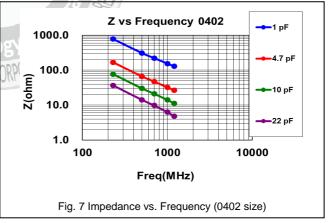


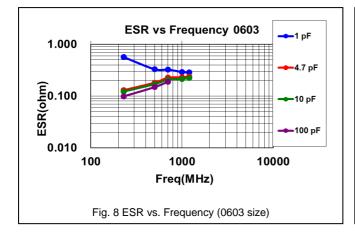


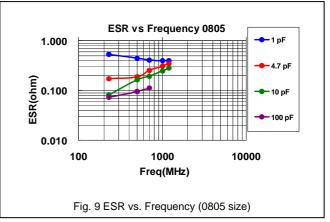


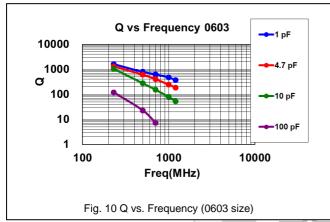


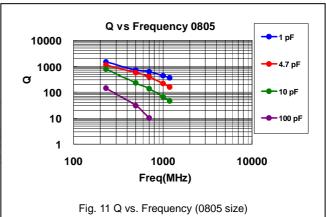


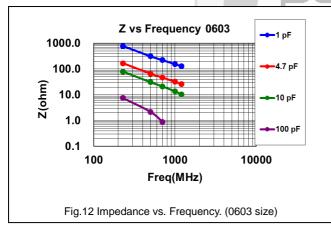


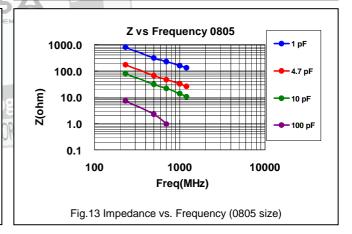


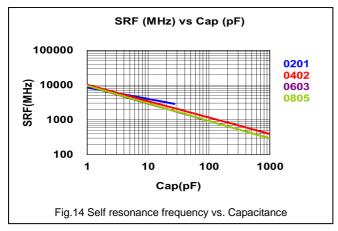














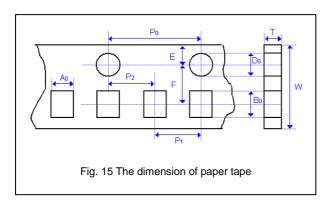
10. RELIABILITY TEST CONDITIONS AND REQUIREMENTS

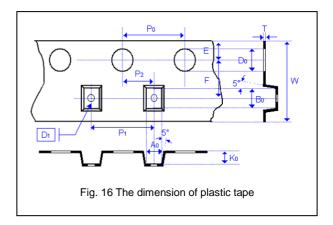
No.	Item	Test Conditions	Requirements
1.	Visual and		* No remarkable defect.
	Mechanical		* Dimensions to conform to individual specification sheet.
2.	Capacitance	Cap≤1000pF, 1.0±0.2Vrms, 1MHz±10%	* Shall not exceed the limits given in the detailed spec.
3.	Q/ D.F.	Cap>1000pF, 1.0±0.2Vrms, 1KHz±10%	* NP0: Cap≥30pF, Q≥1000; Cap<30pF, Q≥400+20C
	(Dissipation	At 25℃ ambient temperature.	
	Factor)		
4.	Dielectric	* To apply voltage: (≤100V) 250% of rated voltage.	* No evidence of damage or flash over during test.
	Strength	* Duration: 1 to 5 sec.	
		* Charge and discharge current less than 50mA.	
		* To apply voltage:	
		200V~300V ≥2 times VDC	
		500V~999V ≥1.5 times VDC	
		* Cut-off, set at 10mA	
		* TEST= 15 sec.	
		* RAMP=0	
5.	Insulation	Rated voltage:<200V	≥10GΩ
	Resistance	To apply rated voltage for max. 120 sec.	
		Rated voltage:200~630V	≥10GΩ or RxC≥100Ω-F whichever is smaller
		To apply rated voltage (500V max.) for 60 sec.	\$.SL
6.	Temperature	With no electrical load.	* Capacitance change: within ±30ppm/℃
	Coefficient	Operating temperature: -55~125℃ at 25℃	
7.	Adhesive	* Pressurizing force :	* No remarkable damage or removal of the terminations.
	Strength of	5N (≤0603) and 10N (>0603)	
	Termination	* Test time: 10±1 sec.	
8.	Vibration	* Vibration frequency: 10~55 Hz/min.	* No remarkable damage.
	Resistance	* Total amplitude: 1.5mm	* Cap change and Q/D.F.: To meet initial spec.
		* Test time: 6 hrs. (Two hrs each in three mutually	2 6
		perpendicular directions.)	
		* Cap./DF(Q) Measurement to be made after de-aging at	
		150℃ for 1hr then set for 24±2 hrs at room temp.	019,000
9.	Solderability	* Solder temperature: 235±5℃	95% min. coverage of all metalized area.
		* Dipping time: 2±0.5 sec.	
10.	Bending Test	* The middle part of substrate shall be pressurized by means	* No remarkable damage.
		of the pressurizing rod at a rate of about 1 mm per second until	* Cap change: within ±5.0% or ±0.5pF whichever is larger.
		the deflection becomes 1 mm and then the pressure shall be	(This capacitance change means the change of capacitance under
		maintained for 5±1 sec.	specified flexure of substrate from the capacitance measured before
		* Measurement to be made after keeping at room temp. for	the test.)
		24±2 hrs.	
11.	Resistance to	* Solder temperature: 260±5℃	* No remarkable damage.
	Soldering Heat	* Dipping time: 10±1 sec	* Cap change: within ±2.5% or ±0.25pF whichever is larger.
		* Preheating: 120 to 150℃ for 1 minute before imme rse the	* Q/D.F., I.R. and dielectric strength: To meet initial requirements.
		capacitor in a eutectic solder.	* 25% max. leaching on each edge.
		* Cap. / DF(Q) / I.R. Measurement to be made after de-aging	
		at 150℃ for 1hr then set for 24±2 hrs at room temp.	

Conduct the five cycles according to the temperatures and time. Step Temp. (**C) Time (min.)	No.	Item	Test Condition			Requirements				
Step Temp. (C) Time (min.)	12.	Temperature	* Conduct the five cycles according to the temperatures and			* No remarkable damage.				
1 Min. operating temp. +0/-3 30±3 2-3 3 Max. operating temp. +3/-0 30±3 4 Room temp. 2-3 3 4 Room temp. 2-3 3 2-2 3 3 2-2 3 2-2 3 2-2 2 2-2 2 2 2		Cycle				* Cap change: within ±2.5% or ±0.25pF whichever is larger.				
2 Room temp. 2-3 3 Max. operating temp. +3/-0 30±3 4 Room temp. 2-3 * Cap. / DF(Q) / I.R. Measurement to be made after de-aging at 150°C for 1hr then set for 24±2 hrs at room temp . * No remarkable damage. * Cap. / DF(Q) / I.R. Measurement to be made after de-aging at 150°C for 1hr then set for 24±2 hrs at room temp . * No remarkable damage. * Cap. damage. * No remarkable damage. * No remarkable damage. * Cap. damage.			•	,	· · ·		* Q/D.F., I.R. and dielectric strength: To meet initial requirements.			
3 Max. operating temp. +3/-0 30±3 4 Room temp. 2-3 * Cap. / DF(Q) / I.R. Measurement to be made after de-aging at 150°C for 1hr then set for 24±2 hrs at room temp. * No remarkable damage. * No remarkable damage. * Cap change: within ±5.0% or ±0.5pF whichever is larger. * Q/D.F. value: NP0: Cap≥30pF, Q≥350; 10pF≤Cap<30pF, Q≥275+2.5C Cap-10pF; Q≥200+10C * I.R.: ≥1GΩ0 r RxC≥50Ω-F whichever is smaller. 14. Humidity (Damp Heat) Load * Test time: 500+24/-0 hrs. * To apply voltage: rated voltage (Max. 500V) * Cap. / DF(Q) / I.R. Measurement to be made after de-aging at 150°C for 1hr then set for 24±2 hrs at room temp. 15. High Temperature Load * To apply voltage: (Endurance) * Test temp.: NP0: 125±3°C Cap <10pF; Q≥200; Cap <30pF, Q≥200; Cap <30pF, Q≥100+10/3C * I.R.: ≥500MΩ or RxC≥25Ω-F whichever is smaller. * No remarkable damage. * Cap change: within ±5.% or ±0.75pF whichever is larger. * Q/D.F. value: NP0: Cap≥30pF, Q≥200; Cap <30pF, Q≥100+10/3C * I.R.: ≥500MΩ or RxC≥25Ω-F whichever is smaller. * No remarkable damage. * Cap change: within ±7.5% or ±0.75pF whichever is larger. * Q/D.F. value: NP0: Cap≥30pF, Q≥200; Cap <30pF, Q≥100+10/3C * I.R.: ≥500MΩ or RxC≥25Ω-F whichever is smaller. * No remarkable damage. * Ozp -10pF, Q≥200; Cap <30pF, Q≥100+10/3C * I.R.: ≥600MΩ or RxC≥25Ω-F whichever is larger. * Q/D.F. value: NP0: Cap≥30pF, Q≥200; Cap <30pF, Q≥200+10C * I.R.: ≥10Ω or RxC≥5Ω-F whichever is larger. * Ozp <10pF, Q≥200+10C * I.R.: ≥10Ω or RxC≥5Ω-F whichever is smaller. * No remarkable damage. * Cap change: within ±3.0% or ±0.3pF whichever is larger. * Ozp <10pF, Q≥200+10C * I.R.: ≥10Ω or RxC≥5Ω-F whichever is smaller. * No remarkable damage. * Cap change: within ±5.0% or ±0.75pF whichever is larger. * Ozp -10pF, Q≥200+10C * I.R.: ≥10Ω or RxC≥5Ω-F whichever is smaller. * No remarkable damage. * Cap change: within ±5.0% or ±0.75pF whichever is larger. * Ozp -10pF, Q≥200+10C * I.R.: ≥10Ω or RxC≥5Ω-F whichever is smaller. * No remarkable damage. * Ozp -10pF, Q≥200+10C * I.R.: ≥10Ω or RxC≥5Ω-F whichever is				<u> </u>						
4 Room temp. 2-3 * Cap. / DF(Q) / I.R. Measurement to be made after de-aging at 150°C for 1hr then set for 24±2 hrs at room temp.			1	ì	1					
**Cap. / DF(Q) / I.R. Measurement to be made after de-aging at 150°C for 1hr then set for 24±2 hrs at room temp. **Test temp: 40±2°C			! -	· · · · · · · · · · · · · · · · · · ·						
13. Humidity (Damp Heat) Steady State * Humidity: 90-95% RH Steady State * Test time: 500+24/-0hrs. * Cap. / DF(Q) / I.R. Measurement to be made after de-aging at 150°C for 1hr then set for 24±2 hrs at room temp. 14. Humidity (Damp Heat) * Test time: 500+24/-0 hrs. * Cap. / DF(Q) / I.R. Measurement to be made after de-aging at 150°C for 1hr then set for 24±2 hrs at room temp. 15. High Temperature Load * Test temp.: 40±2°C * Load * Test time: 500+24/-0 hrs. * To apply voltage: rated voltage (Max. 500V) * Cap. / DF(Q) / I.R. Measurement to be made after de-aging at 150°C for 1hr then set for 24±2 hrs at room temp. 16. High Temperature Load * To apply voltage: (Endurance) * To apply voltage: (1) <500V: 200% of rated voltage. (2) 500V: 150% of rated voltage. (3) ≥630V: 120% of rated voltage. * Cap. / DF(Q) / I.R. Measurement to be made after de-aging * No remarkable damage. * No remarkable damage. * No remarkable damage. * Cap change: within ±7.5% or ±0.75pF whichever is larger. * Q/D.F. value: NPO: Cap≥30pF, Q≥200; Cap<30pF, Q≥100+10/3C * I.R.: ≥500MΩ or RxC≥5Ω-F whichever is smaller. * No remarkable damage. * O/D.F. value: NPO: Cap≥30pF, Q≥200; Cap<30pF, Q≥100+10/3C * No remarkable damage. * O/D.F. value: NPO: Cap≥30pF, Q≥200; Cap<30pF, Q≥100+10/3C * No remarkable damage. * O/D.F. value: NPO: Cap≥30pF, Q≥200; Cap<30pF, Q≥100+10/3C * O/D.F. value: NPO: Cap≥30pF, Q≥200; Cap<30pF, Q≥200; Cap<3			:			iina				
Camp Heat Steady State Test time: 500+24/-0hrs. Cap. / DF(Q) / I.R. Measurement to be made after de-aging at 150°C for 1hr then set for 24±2 hrs at room temp. Test time: 500+24/-0 hrs. Test time: 500+24/-0 hrs. To apply voltage: rated voltage (Max. 500V) Cap. / DF(Q) / I.R. Measurement to be made after de-aging at 150°C for 1hr then set for 24±2 hrs at room temp. Test time: 500+24/-0 hrs. To apply voltage: rated voltage (Max. 500V) Cap. / DF(Q) / I.R. Measurement to be made after de-aging at 150°C for 1hr then set for 24±2 hrs at room temp. Temperature Load Temperature Load To apply voltage: (I) <500V: 200% of rated voltage. (2) 500V: 150% of rated voltage. (2) 500V: 150% of rated voltage. Test time: 1000+24/-0 hrs. Test tim				` '	-	, <u>9</u>				
Steady State * Test time: 500+24/-0hrs. * Cap. / DF(Q) / I.R. Measurement to be made after de-aging at 150°C for 1hr then set for 24±2 hrs at room temp . * Cap. / DF(Q) / I.R. Measurement to be made after de-aging at 150°C for 1hr then set for 24±2 hrs at room temp . * Cap. / DF(Q) / I.R. Death of the properties o	13.	Humidity	* Test ten	np.: 40±2℃			* No remarkable damage.			
* Cap. / DF(Q) / I.R. Measurement to be made after de-aging at 150°C for 1hr then set for 24±2 hrs at room temp . **NPO: Cap≥30pF, Q≥350; 10pF≤Cap<30pF, Q≥275±2.5C Cap<10pF; Q≥200±10C **I.R.: ≥1GΩor RxC≥50Ω-F whichever is smaller. **No remarkable damage. **Cap change: within ±7.5% or ±0.75pF whichever is larger. **Op. / DF(Q) / I.R. Measurement to be made after de-aging at 150°C for 1hr then set for 24±2 hrs at room temp. **Test temp.: **No remarkable damage. **Cap change: within ±7.5% or ±0.75pF whichever is larger. **Q/D.F. value: **NPO: Cap≥30pF, Q≥200; Top ±0.75pF whichever is larger. **Q/D.F. value: **NPO: Cap≥30pF, Q≥200; Top ±0.75pF whichever is smaller. **Cap change: within ±3.0% or ±0.3pF whichever is larger. **Op. F. value: **No remarkable damage. **Cap change: within ±3.0% or ±0.3pF whichever is larger. **Q/D.F. value: **NPO: Cap≥30pF, Q≥250; Top ±0.75pF whichever is smaller. **No remarkable damage. **Cap change: within ±3.0% or ±0.3pF whichever is larger. **Q/D.F. value: **NPO: Cap≥30pF, Q≥350 **Q/D.F. value: **NPO: Cap≥30pF, Q≥350 **Q/D.F. value: **NPO: Cap≥30pF, Q≥275±2.5C **Cap change: within ±3.0% or ±0.3pF whichever is larger. **Q/D.F. value: **NPO: Cap≥30pF, Q≥350 **Q/D.F. value: **NPO: Cap≥30pF, Q≥275±2.5C **Cap change: within ±3.0% or ±0.3pF whichever is larger. **Q/D.F. value: **NPO: Cap≥30pF, Q≥350 **Q/D.F. value: **NPO: Cap≥30pF, Q≥275±2.5C **Cap change: within ±3.0% or ±0.3pF whichever is larger. **Q/D.F. value: **Q/D.F. value: **NPO: Cap≥30pF, Q≥275±2.5C **Cap<10pF, Q≥200±10C **Test time: 1000±24/-0 hrs. **Cap. / DF(Q) / I.R. Measurement to be made after de-aging		(Damp Heat)	* Humidit	y: 90~95% RH			* Cap change: within ±5.0% or ±0.5pF whichever is larger.			
at 150°C for 1hr then set for 24±2 hrs at room temp . Cap<10pF; Q≥200+10C * I.R.: ≥1GΩor RxC≥50Ω-F whichever is smaller. * No remarkable damage. Cap change: within ±7.5% or ±0.75pF whichever is larger. * Cap change: within ±7.5% or ±0.75pF whichever is larger. * Cap change: within ±7.5% or ±0.75pF whichever is larger. * O/D.F. value: NP0: Cap≥30pF, Q≥200; Cap<30pF, Q≥100+10/3C * I.R.: ≥500MΩ or RxC≥25Ω-F whichever is smaller. * No remarkable damage. * No remarkable damage. * No remarkable damage. * Cap change: within ±3.0% or ±0.3pF whichever is larger. * No remarkable damage. * O/D.F. value: NP0: 125±3°C Cap change: within ±3.0% or ±0.3pF whichever is larger. * O/D.F. value: NP0: Cap≥30pF, Q≥350 (2) 500V: 150% of rated voltage. (2) 500V: 150% of rated voltage. * O/D.F. value: NP0: Cap≥30pF, Q≥350 10pF≤Cap<30pF, Q≥275+2.5C Cap<10pF, Q≥200+10C * I.R.: ≥1GΩ or RxC≥50Ω-F whichever is smaller.		Steady State	* Test tim	e: 500+24/-0hrs.			* Q/D.F. value:			
* I.R.: ≥1GΩor RxC≥50Ω-F whichever is smaller. 14. Humidity (Damp Heat) Load * Test temp: 40±2℃ * Humidity: 90~95%RH Load * Test time: 500+24/-0 hrs. * To apply voltage: rated voltage (Max. 500V) * Cap. / DF(Q) / I.R. Measurement to be made after de-aging at 150℃ for 1hr then set for 24±2 hrs at room temp. 15. High Temperature Load * To apply voltage: (Endurance) (1) <500V: 200% of rated voltage. (2) 500V: 150% of rated voltage. (3) ≥630V: 120% of rated voltage. * Test time: 1000+24/-0 hrs. * Cap. / DF(Q) / I.R. Measurement to be made after de-aging at 150℃ for 1hr then set for 24±2 hrs at room temp. * No remarkable damage. * Cap change: within ±3.0% or ±0.3pF whichever is larger. Q/D.F. value: NP0: Cap≥30pF, Q≥350 10pF≤Cap<30pF, Q≥275+2.5C Cap<10pF, Q≥275+2.5C Cap<10pF, Q≥200+10C * I.R.: ≥1GΩ or RxC≥50Ω-F whichever is smaller.			* Cap. / D	F(Q) / I.R. Measurement to be	made after de-ag	jing	NP0: Cap≥30pF, Q≥350; 10pF≤Cap<30pF, Q≥275+2.5C			
Humidity							Cap<10pF; Q≥200+10C			
Cap change: within ±7.5% or ±0.75pF whichever is larger.							* I.R.: ≥1GΩor RxC≥50Ω-F whichever is smaller.			
Load * Test time: 500+24/-0 hrs.	14.	Humidity	* Test temp.: 40±2°C				* No remarkable damage.			
* To apply voltage: rated voltage (Max. 500V) * Cap. / DF(Q) / I.R. Measurement to be made after de-aging at 150°C for 1hr then set for 24±2 hrs at room temp. 15. High Temperature Load * To apply voltage: NP0: Cap≥30pF, Q≥200; Cap<30pF, Q≥100+10/3C * I.R.: ≥500MΩ or RxC≥25Ω-F whichever is smaller. * No remarkable damage. * Cap change: within ±3.0% or ±0.3pF whichever is larger. * Q/D.F. value: NP0: Cap≥30pF, Q≥350 * Op.F. value: NP0: Cap≥30pF, Q≥200+10C * Test time: 1000+24/-0 hrs. * Cap. / DF(Q) / I.R. Measurement to be made after de-aging		(Damp Heat)	* Humidit	y: 90~95%RH			* Cap change: within ±7.5% or ±0.75pF whichever is larger.			
* Cap. / DF(Q) / I.R. Measurement to be made after de-aging at 150°C for 1hr then set for 24±2 hrs at room temp. * I.R.: ≥500MΩ or RxC≥25Ω-F whichever is smaller. * I.R.: ≥500MΩ or RxC≥25Ω-F whichever is smaller. * No remarkable damage. * No remarkable damage. * Cap change: within ±3.0% or ±0.3pF whichever is larger. * Q/D.F. value: * NP0: Cap≥30pF, Q≥350 * 10pF≤Cap<30pF, Q≥275+2.5C * Cap<10pF, Q≥200+10C * Test time: 1000+24/-0 hrs. * Cap. / DF(Q) / I.R. Measurement to be made after de-aging * I.R.: ≥1GΩ or RxC≥50Ω-F whichever is smaller.		Load	* Test tim	e: 500+24/-0 hrs.			* Q/D.F. value:			
at 150°C for 1hr then set for 24±2 hrs at room temp. 15. High Temperature Load (Endurance) (1) <500V: 200% of rated voltage. (2) 500V: 150% of rated voltage. (3) ≥630V: 120% of rated voltage. * Test time: 1000+24/-0 hrs. * Cap. / DF(Q) / I.R. Measurement to be made after de-aging* * No remarkable damage. * Cap change: within ±3.0% or ±0.3pF whichever is larger. * Q/D,F. value: NP0: Cap≥30pF, Q≥350 10pF≤Cap<30pF, Q≥275+2.5C Cap<10pF, Q≥200+10C * I.R.: ≥1GΩ or RxC≥50Ω-F whichever is smaller.			* To apply	y voltage: rated voltage (Max.	500V)		NP0: Cap≥30pF, Q≥200; Cap<30pF, Q≥100+10/3C			
15. High			* Cap. / D	F(Q) / I.R. Measurement to be	made after de-ag	jing	* I.R.: ≥500MΩ or RxC≥25Ω-F whichever is smaller.			
Temperature Load * To apply voltage: (Endurance) (2) 500V: 150% of rated voltage. (3) ≥630V: 120% of rated voltage. * Test time: 1000+24/-0 hrs. * Cap change: within ±3.0% or ±0.3pF whichever is larger. * Q/D.F. value: NP0: Cap≥30pF, Q≥350 10pF≤Cap<30pF, Q≥275+2.5C Cap<10pF, Q≥200+10C * I.R.: ≥1GΩ or RxC≥50Ω-F whichever is smaller.			at 150℃	for 1hr then set for 24±2 hrs a	t room temp.	1	#			
Load * To apply voltage: (I) <500V: 200% of rated voltage. (2) 500V: 150% of rated voltage. (3) ≥630V: 120% of rated voltage. * Test time: 1000+24/-0 hrs. * Cap. / DF(Q) / I.R. Measurement to be made after de-aging * Q/D.F. value: NP0: Cap≥30pF, Q≥350 10pF≤Cap<30pF, Q≥275+2.5C Cap<10pF, Q≥200+10C * I.R.: ≥1GΩ or RxC≥50Ω-F whichever is smaller.	15.	High	* Test ten	np.:			* No remarkable damage.			
(Endurance) (1) <500V: 200% of rated voltage. (2) 500V: 150% of rated voltage. (3) ≥630V: 120% of rated voltage. (4) × 120× 0 × 120×		Temperature	NP0: 12	25±3℃	、话股1	77 2	* Cap change: within ±3.0% or ±0.3pF whichever is larger.			
(2) 500V: 150% of rated voltage. (3) ≥630V: 120% of rated voltage. * Test time: 1000+24/-0 hrs. * Cap. / DF(Q) / I.R. Measurement to be made after de-aging 10pF≤Cap<30pF, Q≥275+2.5C Cap<10pF, Q≥200+10C * I.R.: ≥1GΩ or RxC≥50Ω-F whichever is smaller.		Load	* To apply	y voltage:	XXX		* Q/D.F. value:			
(3) ≥630V: 120% of rated voltage. * Test time: 1000+24/-0 hrs. * Cap. / DF(Q) / I.R. Measurement to be made after de-aging Cap<10pF, Q≥200+10C * I.R.: ≥1GΩ or RxC≥50Ω-F whichever is smaller.		(Endurance)					NP0: Cap≥30pF, Q≥350			
* Test time: 1000+24/-0 hrs. * Cap. / DF(Q) / I.R. Measurement to be made after de-aging * I.R.: ≥1GΩ or RxC≥50Ω-F whichever is smaller.			(2) 500V:	150% of rated voltage.			10pF≤Cap<30pF, Q≥275+2.5C			
* Cap. / DF(Q) / I.R. Measurement to be made after de-aging			(3) ≥630\	/: 120% of rated voltage.			Cap<10pF, Q≥200+10C			
			* Test tim	e: 1000+24/-0 hrs.			* I.R.: ≥1GΩ or RxC≥50Ω-F whichever is smaller.			
at 150℃ for 1hr then set for 24±2 hrs at room temp.			* Cap. / D	DF(Q) / I.R. Measurement to be	made after de-ag	ing	TANCE CS			
			at 150℃ i	for 1hr then set for 24±2 hrs at	room temp.		2 2			

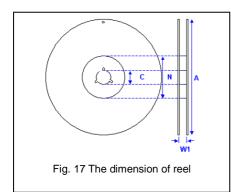
APPENDIXES

■ Tape & reel dimensions





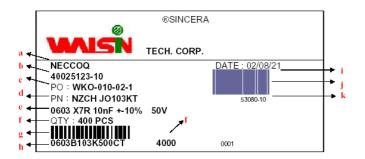
Size	0201	0402	0603		0805	
Thickness	L	N	S, X	Α	В	C, D, I
A ₀	0.39 +/-0.07	0.70 +/-0.2	1.05 +/-0.30	1.50 +/-0.20	1.50 +/-0.20	< 1.80
B_0	0.69 +/-0.07	1.20 +/-0.2	1.80	2.30 +/-0.20	2.30 +/-0.20	< 2.70
Т	≦0.50	≦0.80	≦1.20	≦1.15	≦1.30	0.23 +/-0.1
K ₀	=	XV XX.	- 3/1/2	131	=	< 2.50
W	8.00	8.00	8.00	8.00	8.00	8.00
	+/-0.10	+/-0.10	+/-0.10	+/-0.10	+/-0.10	+/-0.20
P ₀	4.00	4.00	4.00	4.00	4.00	4.00
	+/-0.10	+/-0.10	+/-0.10	+/-0.10	+/-0.10	+/-0.10
10xP ₀	40.00	40.00	40.00	40.00	40.00	40.00
	+/-0.10	+/-0.10	+/-0.20	+/-0.20	+/-0.20	+/-0.20
P ₁	2.00	2.00	4.00	4.00	4.00	4.00
	+/-0.05	+/-0.05	+/-0.10	+/-0.10	+/-0.10	+/-0.10
P ₂	2.00	2.00	2.00	2.00	2.00	2.00
	+/-0.05	+/-0.05	+/-0.05	+/-0.05	+/-0.05	+/-0.05
D_0	1.55	1.55	1.55	1.55	1.55	1.50
	+/-0.05	+/-0.05	+/-0.05	+/-0.05	+/-0.05	+0.1/-0
D ₁	-	ALSM17	hology	Wilkin-	=	1.00 +/-0.10
Е	1.75	1.75	1.75	1.75	1.75	1.75
	+/-0.05	+/-0.05	(-/-0.05	+/-0.05	+/-0.05	+/-0.10
F	3.50	3.50	3.50	3.50	3.50	3.50
	+/-0.05	+/-0.05	+/-0.05	+/-0.05	+/-0.05	+/-0.05



Size	0201, 0402, 0603, 0805						
Reel size	7"	10"	13"				
С	13.0+0.5/-0.2	13.0+0.5/-0.2	13.0+0.5/-0.2				
W ₁	8.4+1.5/-0	8.4+1.5/-0	8.4+1.5/-0				
Α	178.0±1.0	250.0±1.0	330.0±1.0				
N	60.0+1.0/-0	100.0±1.0	100±1.0				



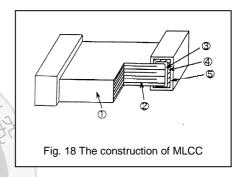
Description of customer label



- a. Customer name
- b. WTC order series and item number
- c. Customer P/O
- d. Customer P/N
- e. Description of product
- f. Quantity
- g. Bar code including quantity & WTC P/N or customer
- h. WTC P/N
- i. Shipping date
- j. Order bar code including series and item numbers
- k. Serial number of label

Constructions

No.	Na	me	NP0
1	Ceramic	material	BaTiO₃ based
2	Inner el	ectrode	斯角
3		Inner layer	K Cu 份本
4	Termination	Middle layer	Ni
(5)		Outer layer	Sn Sn



Storage and handling conditions

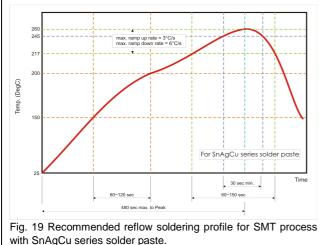
- (1) To store products at 5 to 40°C ambient temperature and 20 to 70%, related humidity conditions.
- (2) The product is recommended to be used within one year after shipment. Check solderability in case of shelf life extension is needed.

Cautions:

- a. The corrosive gas reacts on the terminal electrodes of capacitors, and results in the poor solderability. Do not store the capacitors in the ambience of corrosive gas (e.g., hydrogen sulfide, sulfur dioxide, chlorine, ammonia gas etc.)
- In corrosive atmosphere, solderability might be degraded, and silver migration might occur to cause low reliability.
- c. Due to the dewing by rapid humidity change, or the photochemical change of the terminal electrode by direct sunlight, the solderability and electrical performance may deteriorate. Do not store capacitors under direct sunlight or dewing condition. To store products on the shelf and avoid exposure to moisture.

■ Recommended soldering conditions

The lead-free termination MLCCs are not only to be used on SMT against lead-free solder paste, but also suitable against lead-containing solder paste. If the optimized solder joint is requested, increasing soldering time, temperature and concentration of N_2 within oven are recommended.



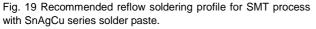




Fig. 20 Recommended wave soldering profile for SMT process with SnAgCu series solder.



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M39014/02-1225V M39014/22-0631 D55342E07B523DR-T/R NCA1206X7R103K50TRPF NCA1206X7R104K16TRPF NIN-FB391JTRF
NIN-FC2R7JTRF NMC0201X5R474K4TRPF NMC0402NPO220J50TRPF NMC0402X5R105K6.3TRPF NMC0402X5R224K6.3TRPF
NMC0402X7R103J25TRPF NMC0402X7R153K16TRPF NMC0603NPO1R8C50TRPF NMC0603NPO201J50TRPF
NMC0603NPO330G50TRPF NMC0603X5R475M6.3TRPF NMC0805NPO270J50TRPF NMC0805NPO820J50TRPF
NMC0805X7R224K25TRPF NMC1206X7R102K50TRPF NMC-H0805X7R472K250TRPF NMC-L0402NPO7R0C50TRPF NMC-L0603NPO2R2B50TRPF NMC-P0805NPO221J500TRPLPF NMC-Q0402NPO8R2D200TRPF C1206C101J1GAC C1608C0G2A221J
C1608X7R1E334K C2012C0G2A472J 2220J2K00562KXT 1812J2K00332KXT CDR31BX103AKWR CDR33BX104AKUR
CDR33BX683AKUS CGA2B2C0G1H010C CGA2B2C0G1H040C CGA2B2C0G1H050C CGA2B2C0G1H060D CGA2B2C0G1H070D
CGA2B2C0G1H120J CGA2B2C0G1H151J CGA2B2C0G1H181JT0Y0F CGA2B2C0G1H1R5C CGA2B2C0G1H6R8D